UCN-4805A BiMOS LATCHED DECODER/DRIVER

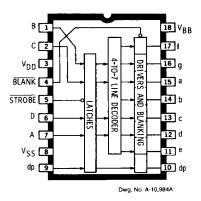
FEATURES

- High-Voltage Source Outputs
- CMOS, PMOS, NMOS, TTL Compatible Inputs
- Low-Power CMOS Latches
- Hexadecimal Decoding
- Internal Pull-Up/Pull-Down Resistors
- Wide Supply Voltage Range

DESIGNED for use in high-voltage vacuum fluorescent display driver applications, the UCN-4805A latched decoder/driver combines CMOS logic with bipolar source outputs. The device consists of eight high-voltage bipolar sourcing outputs, with internal pull-down resistors and CMOS input latches, hexadecimal decoder, and control circuitry (strobe and blanking).

Type UCN-4805A is intended to serve as the segment driver with standard 7-segment displays incorporating a colon or decimal point. The integrated circuit uses hexadecimal decoding to display 0-9, A, b, C, d, E, and F.

This BiMOS latched decoder/driver has sufficient speed to permit operation with most microprocessor/LSI-based systems. The CMOS input latches provide operation over the supply voltage range of 5 to 15 V with minimum logic loading. Internal output pull-down resistors eliminate the need for external components usually required for fluorescent display applications. When used with standard TTL or low-speed TTL logic, the device may require employment of input pull-up resistors to insure a proper input logic high.



UCN-4805A

ABSOLUTE MAXIMUM RATINGS at $+25^{\circ}$ C Free-Air Temperature and $V_{ss} = 0 \text{ V}$

Output Voltage, V _{out}) V
Logic Supply Voltage Range, V _{DD}	3 V
Driver Supply Voltage Range, V _{BB} 5.0 V to 60) V
Input Voltage Range, $V_{IN} \dots -0.3 \text{ V to } V_{DO} + 0.3 $	3 V
Continuous Output Current, I _{OUT}	nΑ
Package Power Dissipation, Pp 1.82 \	N*
Operating Temperature Range, $T_A \cdot \cdot \cdot \cdot \cdot - 20^{\circ}$ C to $+ 85$	°C
Storage Temperature Range, $T_s \dots -55^{\circ}C$ to $+125$	°C

^{*}Derate at the rate of 18.18 mW/°C above T_A = 25°C.

Caution: Sprague CMOS devices feature input static protection but are still susceptible to damage when exposed to extremely high static electrical charges.

ELECTRICAL CHARACTERISTICS at $T_A=25^{\circ}\text{C},\,V_{BB}=60\,\text{V},\,V_{DD}=4.75\,\text{V}$ to 15.75 V, $V_{SS}=0\,\text{V}$ (unless otherwise noted)

			Limits			
Characteristic	Symbol	Test Canditions	Min.	Max.	Units	
Output OFF Voltage	V _{out}		_	1.0	٧	
Output ON Voltage	1	$I_{OUT} = -25 \text{ mA}$	57.5	_	٧	
Output Pull-Down Current	l _{out}	V _{OUT} = V _{BB}	400	850	μA	
Output Leakage Current	1	T _A = 70°C	_	-15	μΑ	
Input Voltage	V _{IN(1)}	$V_{00} = 5.0 \text{ V}$	3.5	5.3	٧	
		$V_{DD} = 15 V$	13.5	15.3	٧	
	V _{IN(0)}		-0.3	+0.8	V	
Input Current	I _{IN(1)}	$V_{DD} = 5.0 \text{ V}$		100	μΑ	
	i	$V_{00} = 15 \text{ V}$		300	μΑ	
Input Impedance	Z _{IN}	$V_{DD} = 5.0 \text{ V}$	50		kΩ	
Supply Current	I _{BB}	Display "8"		9.1	m A	
		All outputs OFF		100	μΑ	
	I _{DD}	$V_{DO} = I/O = STROBE = 5.0 V$, All other inputs $= 0 V$		200	μΑ	
		$V_{DD} = I/O = STROBE = 15 V$, All other inputs = $0 V$		500	μλ	
•		V ₀₀ = STROBE = BLANK = 5.0 V, Data latched, Display "8"	_	7.0	m A	
		V _{DD} = STROBE = BLANK = 15 V, Data latched, Display "8"	_	21	mA	

NOTE: Positive (negative) current is defined as going into (coming out of) the specified device pin.

MAXIMUM ALLOWABLE DUTY CYCLE

Number of Outputs ON	Max. Allowable Duty Cycle at Ambient Temperature of						
$(I_{OUT} = -25 \text{ mA})$	50°C	60°C	70°C				
8	100%	92%	78%				
7	Ť	100%	89%				
6		†	100%				
‡	↓ ·	. ↓	\$				
Ì	100%	100%	100%				

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UCN-4805A TRUTH TABLE

			Inp	uts				Outputs							
D	С	В	A	dp	Βī	ST	Character	а	b	С	d	е	f	g	dp
0	0	0	0	0	1	0	Zero	1	1	1	1	1	1	0	0
0	0	0	1	0	1	0	One	0	1	1	0	0	0	0	0
0	0	1	0	0	1	0	Two	1	1	0	1	1	0	1	0
0	0	1	1	0	1	0	Three	1	1	1	1	0	0	1	0
0	1	0	0	0	1	0	Four	0	1	1	0	0	1	I	0
0	1	0	1	0	1	0	Five	1	0	1	1	0	1	1	0
0	1	1	0	0	1	0	Six	1	0	1	1	1	1	1	0
0	1	1	1	0	1	0	Seven	1	1	1	0	0	0	0	0
1	0	0	0	0	1	0	Eight	1	1	1	1	1	1	1	0
1	0	0	1	0	1	0	Nine	1	1	1	0	0	1	1	0
1	0	1	0	0	1	0	A	1	1	1	0	1	1	1	0
1	0	1	1	0	1	0	b	0	0	1	1	1	1	1	0
1	1	0	0	0	1	0	C	1	0	0	1	1	1	0	0
1	1	0	1	0	1	0	đ	0	1	1	1	1	0	1	0
1	1	1	0	0	1	0	E	1	0	0	1	1	1	1	0
1	1	1	1	0	1	0	F	1	0	0	0	1	1	1	0
X	X	Х	X	1	1	0	dp	Χ	X	X	X	Χ	Χ	X	1
X	Χ	χ	X	X	0	X	blank	0	0	0	0	0	0	0	0

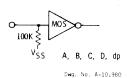


X =_irrelevant

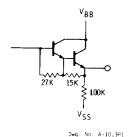
TYPICAL INPUT CIRCUITS

VDD 100K MOS BL, ST

Dwg.No. A-10,979A

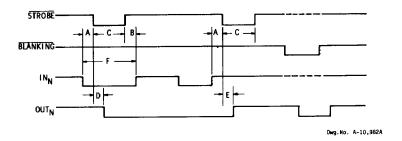


TYPICAL OUTPUT DRIVER



TIMING CONDITIONS

(Logic Levels are Vpp and Vss)



Information present at an input is transferred to its latch when the STROBE (ST) is low. The latches will continue to accept new data as long as the STROBE is held low. Applications where the latches are bypassed (STROBE tied low) ordinarily require that the BLANKING input be low between digit selection because of possible non-synchronous decoding.

When the $\overline{BLANKING}$ (\overline{BL}) input is low, all of the output buffers are disabled (OFF) without affecting the information stored in the latches. With the $\overline{BLANKING}$ input high, the outputs are controlled by the latch/decoder circuitry.